DATA-2014: IEEE INTERNATIONAL WORKSHOP on DEFECTS, ADAPTIVE TEST AND DATA ANALYSIS

Will be held in conjunction with ITC 2014, on Oct 23/24 2014, at the Washington State Convention Center, Seattle, Washington

DATA 2014

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CALL FOR PAPERS AND PARTICIPATION
THEME: "BIG DATA" TECHNIQUES

It's all about the DATA. Everything we do in Test relies on data. We use data to identify our good parts, our bad parts, and our weak parts. We manipulate test data to detect outliers and reliability risks. We use data to control and adjust future testing. We also use data to record the full history of wafer lots and to track baseline production changes. And of course we have to collect all that data, store it, analyze it, secure it, and syndicate it to authorized consumers.

The Organizing Committee for the DATA-2014 Workshop is soliciting papers in the area of semiconductor test data management, analysis, and syndication. Of particular interest are innovations and advancements in: application of "Big Data" analysis techniques to test data, semiconductor test data acquisition methods, data storage and retrieval, security and syndication, analysis methods including data mining, and implementation of adaptive test. Submissions from qualified data management parties outside the semiconductor industry are welcome. Preference will be given to real-world case studies.

Ideas or proposals for Embedded Tutorials, Debates, Panel Discussions and **Poster style "Spot-Light"** presentations describing industrial experiences or research are also invited.

Suggested Topics

- Data storage and security
- Analog Fault modeling and coverage
- Analog effects in Digital Logic
- Embedded Instrumentation (iJTAG)
- Advanced Product Engineering Techniques
- Product and Project Case studies
- Advanced dppm reduction techniques
- Dynamic test elimination based on data
- Adaptive Test for Product Engineers
- Data Analysis methods, including multivariate data
- Fault Localization and Diagnosis
- Yield Learning and Analysis
- I/O Test, Tuning, and Adjustment
- Analysis of Aging and Reliability

To present at the workshop, send to JLRoehr@TI.com a PDF version of an extended abstract or a full paper (Max 10 pages, double column, 11pt font size, IEEE proceeding format) by **September 15, 2014**. Each submission should include full name and address of each author, affiliation, telephone number, FAX and Email address. Camera-ready papers for inclusion in the digest of papers will be due on **October 10, 2014**.

AUTHOR'S SCHEDULE Web-site at: http://DATA.tttc-events.org/

Submission Date:	**September 15, 2014**
Notification of Acceptance:	**October 1, 2014**
Camera Ready Paper (.pdf):	**October 10, 2014**
Final Presentation Slides (.ppt):	**October 15, 2014**

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